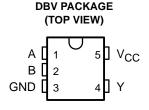
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- Inputs Are TTL-Voltage Compatible
- EPIC[™] (Enhanced-Performance Implanted CMOS) Process
- High Latch-Up Immunity Exceeds 250 mA Per JESD 17
- Packaged in Plastic Small-Outline Transistor Package



description

The SN74AHCT1G00 performs the Boolean function $Y = \overline{A \cdot B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The SN74AHCT1G00 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

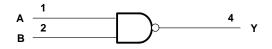
INP	UTS	OUTPUT
Α	В	Υ
Н	Н	L
L	X	Н
Х	L	Н

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
٧ _I	Input voltage	0	5.5	V
VO	Output voltage	0	VCC	V
IOH	High-level output current		-8	mA
l _{OL}	Low-level output current		8	mA
Δt/Δν	Input transition rise or fall rate		20	ns/V
TA	Operating free-air temperature	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	vcc	T _A = 25°C			MIN	MAX	UNIT
	TEST CONDITIONS		MIN	TYP	MAX	IVIIIN	WAX	UNIT
Vou	$I_{OH} = -50 \mu A$	4.5 V	4.4	4.5		4.4		·
VOH	$I_{OH} = -8 \text{ mA}$	4.5 V	3.94			3.8		
V _{OL}	I _{OL} = 50 μA	4.5 V			0.1		0.1	V
	$I_{OL} = 8 \text{ mA}$	4.5 V			0.36		0.44	
lį	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			1		10	μΑ
∆lcc [‡]	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35	·	1.5	mA
C _i	$V_I = V_{CC}$ or GND	5 V		2	10		10	pF

[‡]This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with JESD 51.

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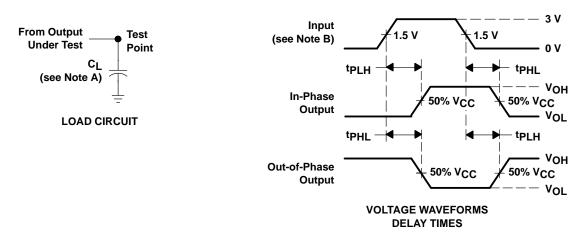
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	T _A = 25°C			MIN	MAX	UNIT		
				MIN	TYP	MAX	IVIIIV	WAA	UNII		
t _{PLH}	A or B	Y	V	D V C: 45 pF	C: - 15 pE		5	6.9	1	8	no
t _{PHL}	AUID		C _L = 15 pF		5	6.9	1	8	ns		
^t PLH	A or B	Y	V C: 50.75		5.5	7.9	1	9			
tPHL	AUID		Y $C_L = 50 \text{ pF}$		5.5	7.9	1	9	ns		

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT
Ср	Power dissipation capacitance	No load, f = 1 MHz	10.5	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- C. The output is measured with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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